

Notice of References Cited	Application/Control No. 10/605,551		Applicant(s)/Patent Under Reexamination OWENS ET AL.	
	Examiner Romain Jeanty		Art Unit 3624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,409,357	08-2008	Schaf et al.	705/7
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Chang et al (Failure mode and effects analysis using grey theory), 12/2001, Integrated Manufacturing Systems Volume: 12 Issue: 3 Page 211-216			
	V	Feather et al (Combining the best attributes of qualitative and quantitative riskmanagement tool support), 12/2000, IEEE, Pages 309-312			
	W	Greenfield (Risk management tools), 5/2000, Langley Research Center, Pages 1-27			
	X	Alexander Carol (Bayesian Methods for Measuring Operational Risk Discussion Papers in Finance 2000-02, ISMA Centre, Pages 1-22			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.